

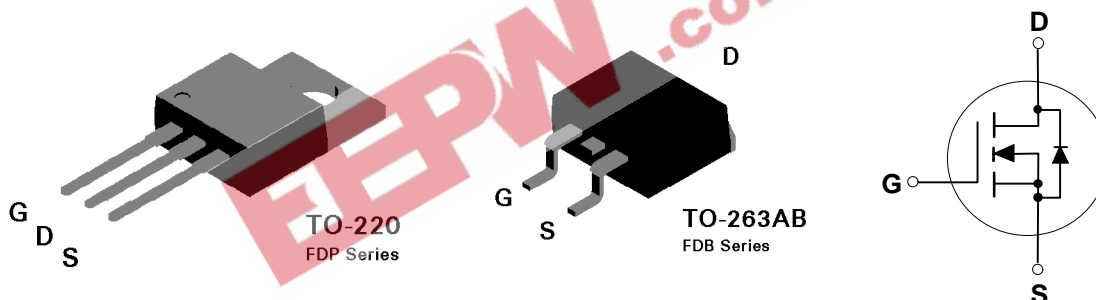
## FDP7030L / FDB7030L N-Channel Logic Level Enhancement Mode Field Effect Transistor

### General Description

These N-Channel logic level enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage applications such as DC/DC converters and high efficiency switching circuits where fast switching, low in-line power loss, and resistance to transients are needed.

### Features

- 100 A, 30 V.  $R_{DS(ON)} = 0.007 \Omega @ V_{GS}=10 \text{ V}$   
 $R_{DS(ON)} = 0.010 \Omega @ V_{GS}=5 \text{ V}$ .
- Critical DC electrical parameters specified at elevated temperature.
- Rugged internal source-drain diode can eliminate the need for an external Zener diode transient suppressor.
- High density cell design for extremely low  $R_{DS(ON)}$ .
- 175°C maximum junction temperature rating.



### Absolute Maximum Ratings $T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	FDP7030L	FDB7030L	Units
$V_{DSS}$	Drain-Source Voltage		30	V
$V_{GSS}$	Gate-Source Voltage - Continuous		$\pm 20$	V
$I_D$	Drain Current - Continuous (Note 1)		100	A
	- Pulsed (Note 1)		75	
$P_D$	Total Power Dissipation @ $T_C = 25^\circ\text{C}$		125	W
	Derate above $25^\circ\text{C}$		0.83	
$T_J, T_{STG}$	Operating and Storage Temperature Range		-65 to 175	$^\circ\text{C}$
$T_L$	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		275	$^\circ\text{C}$
<b>THERMAL CHARACTERISTICS</b>				
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		1.2	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	$^\circ\text{C/W}$

**Electrical Characteristics** ( $T_C = 25^\circ\text{C}$  unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
<b>DRAIN-SOURCE AVALANCHE RATINGS</b> (Note 1)						
$W_{DSS}$	Single Pulse Drain-Source Avalanche Energy	$V_{DD} = 15\text{ V}, I_D = 38\text{ A}$			200	mJ
$I_{AR}$	Maximum Drain-Source Avalanche Current				38	A
<b>OFF CHARACTERISTICS</b>						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{ V}, I_D = 250\ \mu\text{A}$	30			V
$\Delta BV_{DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	$I_D = 250\ \mu\text{A}$ , Referenced to $25^\circ\text{C}$		36		mV/°C
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 24\text{ V}, V_{GS} = 0\text{ V}$ $T_J = 125^\circ\text{C}$			10	$\mu\text{A}$
					1	mA
$I_{GSSF}$	Gate - Body Leakage, Forward	$V_{GS} = 20\text{ V}, V_{DS} = 0\text{ V}$			100	nA
$I_{GSSR}$	Gate - Body Leakage, Reverse	$V_{GS} = -20\text{ V}, V_{DS} = 0\text{ V}$			-100	nA
<b>ON CHARACTERISTICS</b> (Note 2)						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\ \mu\text{A}$	1	1.5	2	V
$\Delta V_{GS(th)}/\Delta T_J$	Gate Threshold Voltage Temp. Coefficient	$I_D = 250\ \mu\text{A}$ , Referenced to $25^\circ\text{C}$		-5		mV/°C
$R_{DS(on)}$	Static Drain-Source On-Resistance	$V_{GS} = 10\text{ V}, I_D = 50\text{ A}$ $T_J = 125^\circ\text{C}$		0.006	0.007	$\Omega$
				0.009	0.01	
$I_{D(on)}$	On-State Drain Current	$V_{GS} = 10\text{ V}, V_{DS} = 10\text{ V}$	60			A
$g_{FS}$	Forward Transconductance	$V_{DS} = 10\text{ V}, I_D = 50\text{ A}$		50		S
<b>DYNAMIC CHARACTERISTICS</b>						
$C_{iss}$	Input Capacitance	$V_{DS} = 15\text{ V}, V_{GS} = 0\text{ V},$ $f = 1.0\text{ MHz}$		2150		pF
$C_{oss}$	Output Capacitance			1290		pF
$C_{rss}$	Reverse Transfer Capacitance			420		pF
<b>SWITCHING CHARACTERISTICS</b> (Note 2)						
$t_{D(on)}$	Turn - On Delay Time	$V_{DD} = 15\text{ V}, I_D = 75\text{ A},$ $V_{GS} = 10\text{ V}, R_{GEN} = 6\ \Omega$ $R_{GS} = 10\ \Omega$		10	20	nS
$t_r$	Turn - On Rise Time			160	225	nS
$t_{D(off)}$	Turn - Off Delay Time			70	95	nS
$t_f$	Turn - Off Fall Time			140	195	nS
$Q_g$	Total Gate Charge	$V_{DS} = 12\text{ V}$ $I_D = 50\text{ A}, V_{GS} = 4.5\text{ V}$		35	50	nC
$Q_{gs}$	Gate-Source Charge			12		nC
$Q_{gd}$	Gate-Drain Charge			18		nC
<b>DRAIN-SOURCE DIODE CHARACTERISTICS</b>						
$I_S$	Maximum Continuous Drain-Source Diode Forward Current (Note 1)				100	A
$I_{SM}$	Maximum Pulsed Drain-Source Diode Forward Current (Note 2)				300	A
$V_{SD}$	Drain-Source Diode Forward Voltage	$V_{GS} = 0\text{ V}, I_S = 50\text{ A}$ (Note 2) $T_J = 125^\circ\text{C}$		1	1.3	V
				0.85	1.1	

**Notes**

1. Calculated continuous current based on maximum allowable junction temperature. Actual maximum continuous current limited by package constraints to 75A.
2. Pulse Test: Pulse Width  $\leq 300\ \mu\text{s}$ , Duty Cycle  $\leq 2.0\%$ .

## Typical Electrical Characteristics

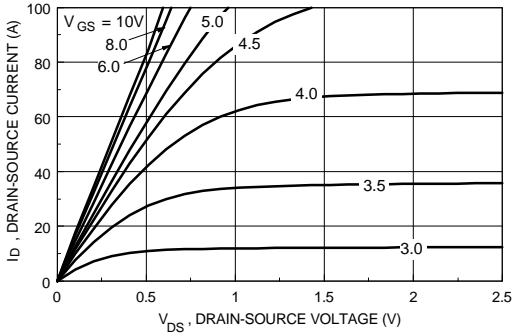


Figure 1. On-Region Characteristics.

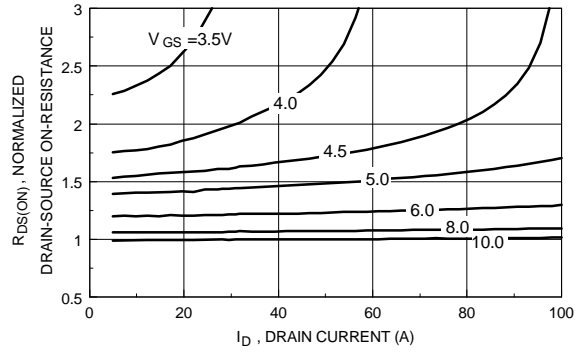


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

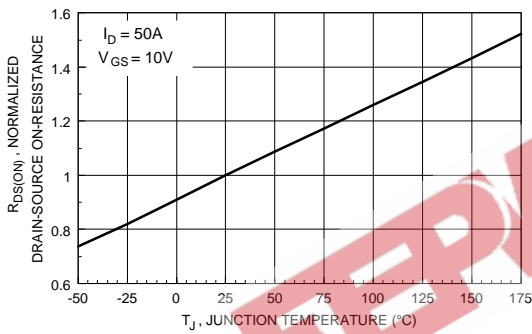


Figure 3. On-Resistance Variation with Temperature.

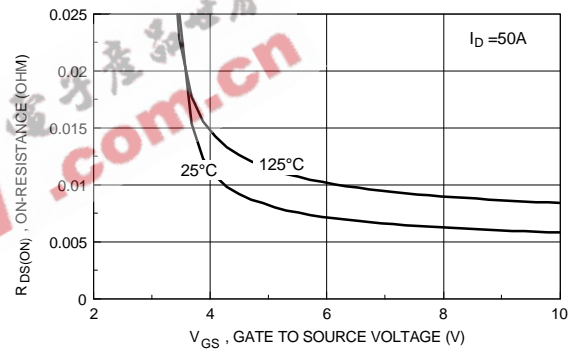


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

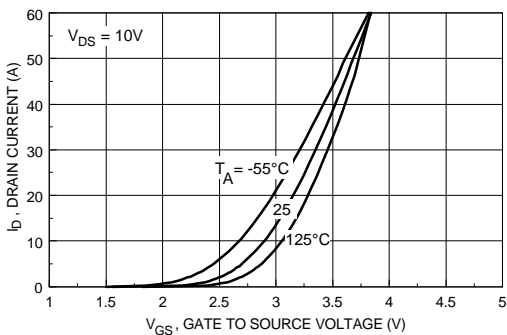


Figure 5. Transfer Characteristics.

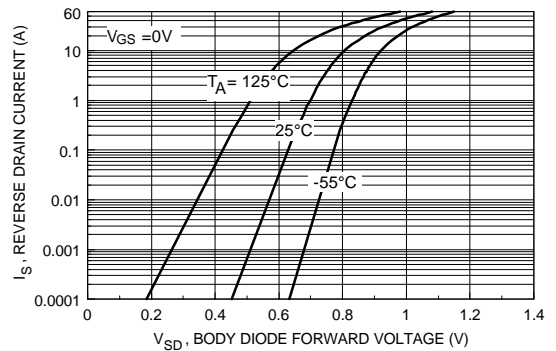
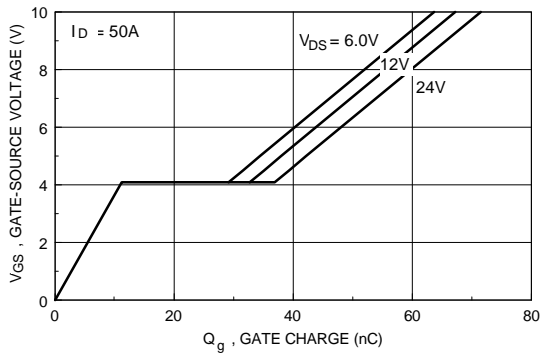
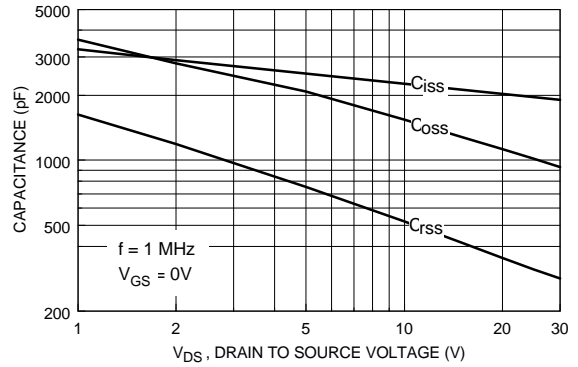


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

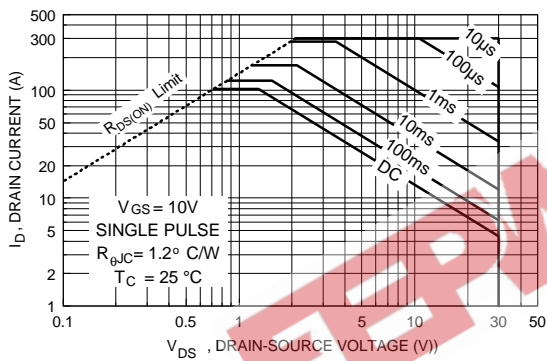
**Typical Electrical Characteristics (continued)**



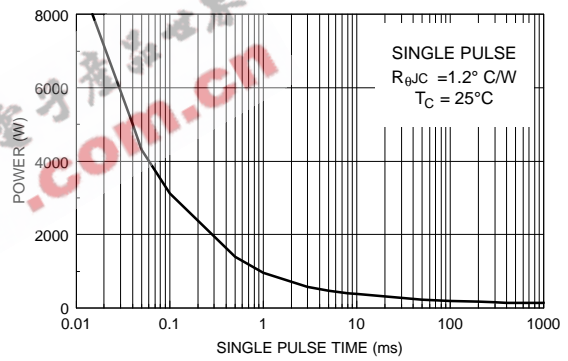
**Figure 7. Gate Charge Characteristics.**



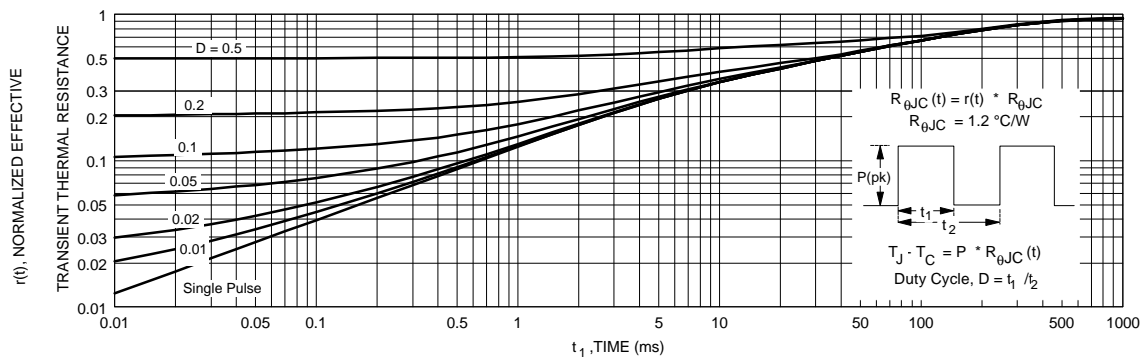
**Figure 8. Capacitance Characteristics.**



**Figure 9. Maximum Safe Operating Area.**



**Figure 10. Single Pulse Maximum Power Dissipation.**



**Figure 11. Transient Thermal Response Curve.**